

Model QT-50/5601TSR

4 POINT PROBE sheet resistance measurement system



QT-50
Manual test stage

5601TSR
Sheet Resistance Tester

4 POINT PROBE sheet resistance measurement system consist of 5601TSR sheet resistance tester and QT-50 manual test stage. This system use the 4 Point Probe principle to measure the sheet resistance and resistivity.

The measurement sample could be wafer, ITO and other semiconductor materials. The dimension of sample could be square or circle. The machine is small, potable and easy operation. Option: QT-60 large manual test stage, QT-70 auto test stage and ST-610A handheld probe.

Functional Performance:

5601TSR sheet resistance tester

Maximun Display:	150000(sheet resistance Ω/\square)/33000(normal resistance Ω)
Sampling Rate:	4 samples/sec
Display:	6 digits, LED dispaly
Overload Indication:	"00000" Flashing
Range selection:	Manual or Auto
Overload protection:	AC 330Vrms
Working voltage:	AC90V~264V, 50/60Hz<15VA
operating temperature:	0~50°C, RH \leq 80%
Communication interface:	RS232, RS485
Baud rate:	1200/2400/4800/9600/19200/38400/57600/115200
Dimension:	208x 91x 280mm

QT-50 manual test stage:

Manual machines under pressure lever arm positioning function for detecting

Needle pressure: Change the pressure by external additive weight 50~500g

Dimension: 300x250x200mm

Test stage size: 156x156, 6" wafer

Weight: 7kg

Application:

- Solar photoelectric material
- Conductive polymeric material
- Transparent conducting films material
- ITO film
- Nano materials
- Micro molecule organic light emitting materials
- Biochip coating materials



QH-1026 Probe Spec:

Probe speacings: 1mm*4

Probe contact resistance: 150m Ω

Probe pressure control among 45g \pm 20%

Maximum current: 1000mA

Needle head: rhodanized Sk4 High Carbon Steel

Circle needle head radii: 150 μ m

Tine needle head radii: <35 μ m; Angle 60°

Weight: 53g

Dimension: 25x40x40mm

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we can supply kinds of test stage to be chosen

QT-60 Large manual test stage

- Wafer size: 8"~12"(300mm)
Square size: 300x300mm
Dimension: 250x320x170mm

QT-SW standard resistance Simulate wafer

- Range: 200m Ohm to 5K Ohm
- Customized value resistance
- Accuracy: 1%
- Standard diameter: 76mm
- Optional calibration report from calibration institution

ST-610A handheld probe

Handheld style, pressing the grip to measure
Suitable for different size of the sample
Dimension: 107mm(H),
52mm (Diameter)
Weight: 290g



ST-610A handheld probe



5601TSR sheet resistance test range

Range Selction	Measuring Range	Resolution	Current output	Accuracy
1500.00mΩ/□	0.01m~1500.00mΩ/□	10μΩ/□	DC 100mA	±0.05%±20digit
15000.0mΩ/□	0.1m~15000.0mΩ/□	100μΩ/□	DC 100mA	±0.02%±10digit
150.000Ω/□	0.001~150.000Ω/□	1mΩ/□	DC 100mA	
1500.00Ω/□	0.01~1500.00Ω/□	10mΩ/□	DC 10mA	
15.0000KΩ/□	0.1~15.0000KΩ/□	100mΩ/□	DC 1mA	
150.000KΩ/□	0.001K~150.000KΩ/□	1Ω/□	DC 100μA	
1500.00KΩ/□	0.01K~1500.00KΩ/□	10Ω/□	DC 10μA	
15000.0KΩ/□	0.1K~15000.0KΩ/□	100Ω/□	DC 1μA	±0.05%±20digit
150.000MΩ/□	0.001M~150.000MΩ/□	1KΩ/□	DC 100nA	